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Terms	Documents
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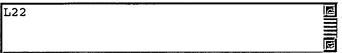
US Pre-Grant Publication Full-Text Database

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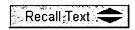
Database:

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Search:











## **Search History**

#### DATE: Friday, September 10, 2004 Printable Copy Create Case

side by	Query	<u>Hit</u> Count	Set Name result
side DR=	=USPT; PLUR=YES; OP=ADJ		set
L22	717/175,140,165.CCLS.	372	L22
<u>L21</u>	717/124,125,126,127.ccls.	639	<u>L21</u>
<u>L20</u>	702/123.ccls.	132	<u>L20</u>
<u>L19</u>	710/8.ccls.	872	<u>L19</u>
<u>L18</u>	714/38.ccls.	803	<u>L18</u>
<u>L17</u>	713/201.ccls.	1385	<u>L17</u>
<u>L16</u>	714/100.ccls.	28	<u>L16</u>
DB=	=TDBD; PLUR=YES; OP=ADJ		
<u>L15</u>	(program\$ or software\$ or application\$) near5 (verif\$ or test\$ or debug\$) and ((program interface) or api) and ((program interface) or api) near5 program\$ and (resource\$ or device\$) near4 constrai\$ and (disabl\$ near5 instal\$)	0	<u>L15</u>
DB=	=DWPI; PLUR=YES; OP=ADJ		

(program\$ or software\$ or application\$) near5 (verif\$ or test\$ or debug\$) and

<u>L14</u>	and (resources) or devices) near4 constrains and (disable near5 instains)					
DB=	=JPAB; PLUR=YES; OP=ADJ					
<u>L13</u>	(program\$ or software\$ or application\$) near5 (verif\$ or test\$ or debug\$) and ((program interface) or api)and ((program interface) or api) near5 program\$ and (resource\$ or device\$) near4 constrai\$ and (disabl\$ near5 instal\$)					
DB=	=EPAB; PLUR=YES; OP=ADJ					
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<u>L11</u>	(program\$ or software\$ or application\$) near5 (verif\$ or test\$ or debug\$) and ((program interface) or api)and ((program interface) or api) near5 program\$ and (resource\$ or device\$) near4 constrai\$ and (disabl\$ near5 instal\$)	0	<u>L11</u>			
DB=PGPB; PLUR=YES; OP=ADJ						
<u>L10</u>	(program\$ or software\$ or application\$) near5 (verif\$ or test\$ or debug\$) and ((program interface) or api)and ((program interface) or api) near5 program\$ and (resource\$ or device\$) near4 constrai\$ and (disabl\$ near5 instal\$)	8	<u>L10</u>			
DB=	=USPT; PLUR=YES; OP=ADJ					
<u>L9</u>	L6 and l2	51	<u>L9</u>			
<u>L8</u>	L6 and 13	0	<u>L8</u>			
<u>L7</u>	L6 and l4	0	<u>L7</u>			
<u>L6</u>	717/124,126,127.ccls.	542	<u>L6</u>			
<u>L5</u>	L4 and (disabl\$ near5 instal\$)	1	<u>L5</u>			
<u>L4</u>	L3 and (instal\$ near5 (resource\$ or device\$))	22	<u>L4</u>			
<u>L3</u>	L2 and (resource\$ or device\$) near4 constrai\$	61	<u>L3</u>			
<u>L2</u>	L1 and ((program interface) or api) near5 program\$	1719	<u>L2</u>			
<u>L1</u>	(program\$ or software\$ or application\$) near5 (verif\$ or test\$ or debug\$) and ((program interface) or api)	2787	<u>L1</u>			

# END OF SEARCH HISTORY

Search:

# **Refine Search**

#### Search Results -

Terms	Documents	
(714/100).ccls.	28	

US Pre-Grant Publication Full-Text Database

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Database: US OCR Full-Text Database EPO Abstracts Database

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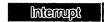
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<u>L16</u>	714/100.ccls.	28	<u>L16</u>
DB=	TDBD; PLUR=YES; OP=ADJ		
<u>L15</u>	(program\$ or software\$ or application\$) near5 (verif\$ or test\$ or debug\$) and ((program interface) or api)and ((program interface) or api) near5 program\$ and (resource\$ or device\$) near4 constrai\$ and (disabl\$ near5 instal\$)	0	<u>L15</u>
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<u>L13</u>	(program\$ or software\$ or application\$) near5 (verif\$ or test\$ or debug\$) and ((program interface) or api)and ((program interface) or api) near5 program\$ and (resource\$ or device\$) near4 constrai\$ and (disabl\$ near5 instal\$)	0	<u>L13</u>
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<u>L12</u>	(program\$ or software\$ or application\$) near5 (verif\$ or test\$ or debug\$) and ((program interface) or api) and ((program interface) or api) near5 program\$ and (resource\$ or device\$) near4 constrai\$ and (disabl\$ near5 instal\$)	0	<u>L12</u>		
DB=	=USOC; PLUR=YES; OP=ADJ				
<u>L11</u>	(program\$ or software\$ or application\$) near5 (verif\$ or test\$ or debug\$) and  ((program interface) or api)and ((program interface) or api) near5 program\$  and (resource\$ or device\$) near4 constrai\$ and (disabl\$ near5 instal\$)				
DB=	=PGPB; PLUR=YES; OP=ADJ				
<u>L10</u>	(program\$ or software\$ or application\$) near5 (verif\$ or test\$ or debug\$) and ((program interface) or api)and ((program interface) or api) near5 program\$ and (resource\$ or device\$) near4 constrai\$ and (disabl\$ near5 instal\$)	8	<u>L10</u>		
DB=USPT; PLUR=YES; OP=ADJ					
<u>L9</u>	L6 and 12	51	<u>L9</u>		
<u>L8</u>	L6 and 13	0	<u>L8</u>		
<u>L7</u>	L6 and l4	0	<u>L7</u>		
<u>L6</u>	717/124,126,127.ccls.	542	<u>L6</u>		
<u>L5</u>	L4 and (disabl\$ near5 instal\$)	1	<u>L5</u>		
<u>L4</u>	L3 and (instal\$ near5 (resource\$ or device\$))	22	<u>L4</u>		
<u>L3</u>	L2 and (resource\$ or device\$) near4 constrai\$	61	<u>L3</u>		
<u>L2</u>	L1 and ((program interface) or api) near5 program\$	1719	<u>L2</u>		
<u>L1</u>	(program\$ or software\$ or application\$) near5 (verif\$ or test\$ or debug\$) and ((program interface) or api)	2787	<u>L1</u>		

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1 Fast detection of communication patterns in distributed executions

Thomas Kunz, Michiel F. H. Seuren

November 1997 Proceedings of the 1997 conference of the Centre for Advanced Studies on Collaborative research

Full text available: pdf(4.21 MB)

Additional Information: full citation, abstract, references, index terms

Understanding distributed applications is a tedious and difficult task. Visualizations based on process-time diagrams are often used to obtain a better understanding of the execution of the application. The visualization tool we use is Poet, an event tracer developed at the University of Waterloo. However, these diagrams are often very complex and do not provide the user with the desired overview of the application. In our experience, such tools display repeated occurrences of non-trivial commun ...

2 Safely executing untrusted code: Model-carrying code: a practical approach for safe execution of untrusted applications



R. Sekar, V.N. Venkatakrishnan, Samik Basu, Sandeep Bhatkar, Daniel C. DuVarney October 2003 Proceedings of the nineteenth ACM symposium on Operating systems principles

Full text available: pdf(301.30 KB)

Additional Information: full citation, abstract, references, citings, index

This paper presents a new approach called model-carrying code (MCC) for safe execution of untrusted code. At the heart of MCC is the idea that untrusted code comes equipped with a concise high-level model of its security-relevant behavior. This model helps bridge the gap between high-level security policies and low-level binary code, thereby enabling analyses which would otherwise be impractical. For instance, users can use a fully automated verification procedure to determine if the code ...

Keywords: mobile code security, policy enforcement, sand-boxing, security policies

Parallel execution of prolog programs: a survey

Gopal Gupta, Enrico Pontelli, Khayri A.M. Ali, Mats Carlsson, Manuel V. Hermenegildo July 2001 ACM Transactions on Programming Languages and Systems (TOPLAS), Volume 23 Issue 4

Full text available: pdf(1.95 MB)

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# 4 Automated modular specification and verification of real-time react systems

Ostroff, J.S.;

Industrial-Strength Formal Specification Techniques, 1995. Proceedings., Wor on , 5-8 April 1995

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